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(12) **United States Design Patent** (10) **Patent No.:** **US D835,799 S**  
**Ito et al.** (45) **Date of Patent:** **\*\* Dec. 11, 2018**

(54) **SUBSTRATE FOR SPECTROSCOPIC ANALYSIS**

9/54; B01L 9/06; B01L 9/52; B01L 9/543; B01L 9/00; B01L 3/5085; B01L 3/5027

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See application file for complete search history.

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(73) Assignee: **HAMAMATSU PHOTONICS K.K.**,  
Hamamatsu-shi, Shizuoka (JP)

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(\*\*) Term: **15 Years**

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(22) Filed: **Sep. 30, 2016**

(Continued)

(80) **Hague Agreement Data**

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*Primary Examiner* — Richard E Chilcot

(57) **CLAIM**

The ornamental design for a substrate for spectroscopic analysis, as shown and described.

(30) **Foreign Application Priority Data**

Apr. 27, 2016 (JP) ..... 2016-009315

(51) **LOC (11) Cl.** ..... **24-02**

(52) **U.S. Cl.**  
USPC ..... **D24/225**  
CPC ..... **G01N 1/405** (2013.01)

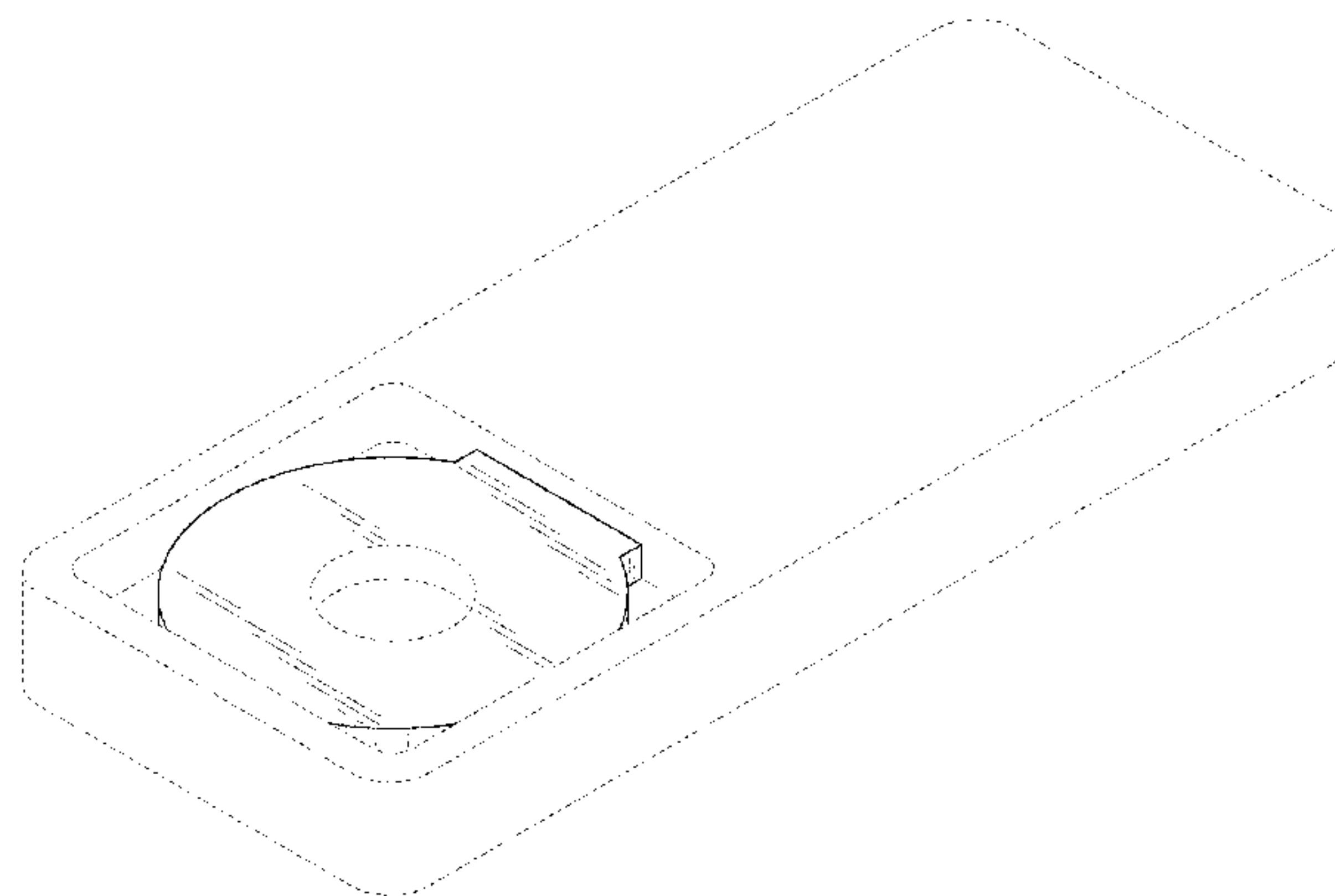
(58) **Field of Classification Search**  
USPC ..... D24/216, 222–226, 231, 232, 169;  
D10/80, 81; 422/502–507, 430, 560–566,  
422/68.1, 69, 547; 435/288.2–288.5,  
435/283.1, 289.1, 44, 46  
CPC ..... B01J 19/0046; B01J 2219/00596; G01N  
1/405; G01N 35/00009; G01N 1/312;  
B01L 2300/0816; B01L 2400/0406; B01L

**DESCRIPTION**

- 1. Substrate for spectroscopic analysis
- 1.1 : Perspective
- 1.2 : Front
- 1.3 : Back
- 1.4 : Top
- 1.5 : Bottom
- 1.6 : Left
- 1.7 : Right
- 1.8 : SECTIONAL VIEW
- 1.9 : SECTIONAL VIEW

The broken line showing the substrate for spectroscopic analysis is for the purpose of illustrating environmental structure and forms no part of the claimed design.

(Continued)



The dot-dash broken lines define the bounds of the claimed design and form no part thereof.

**1 Claim, 9 Drawing Sheets**

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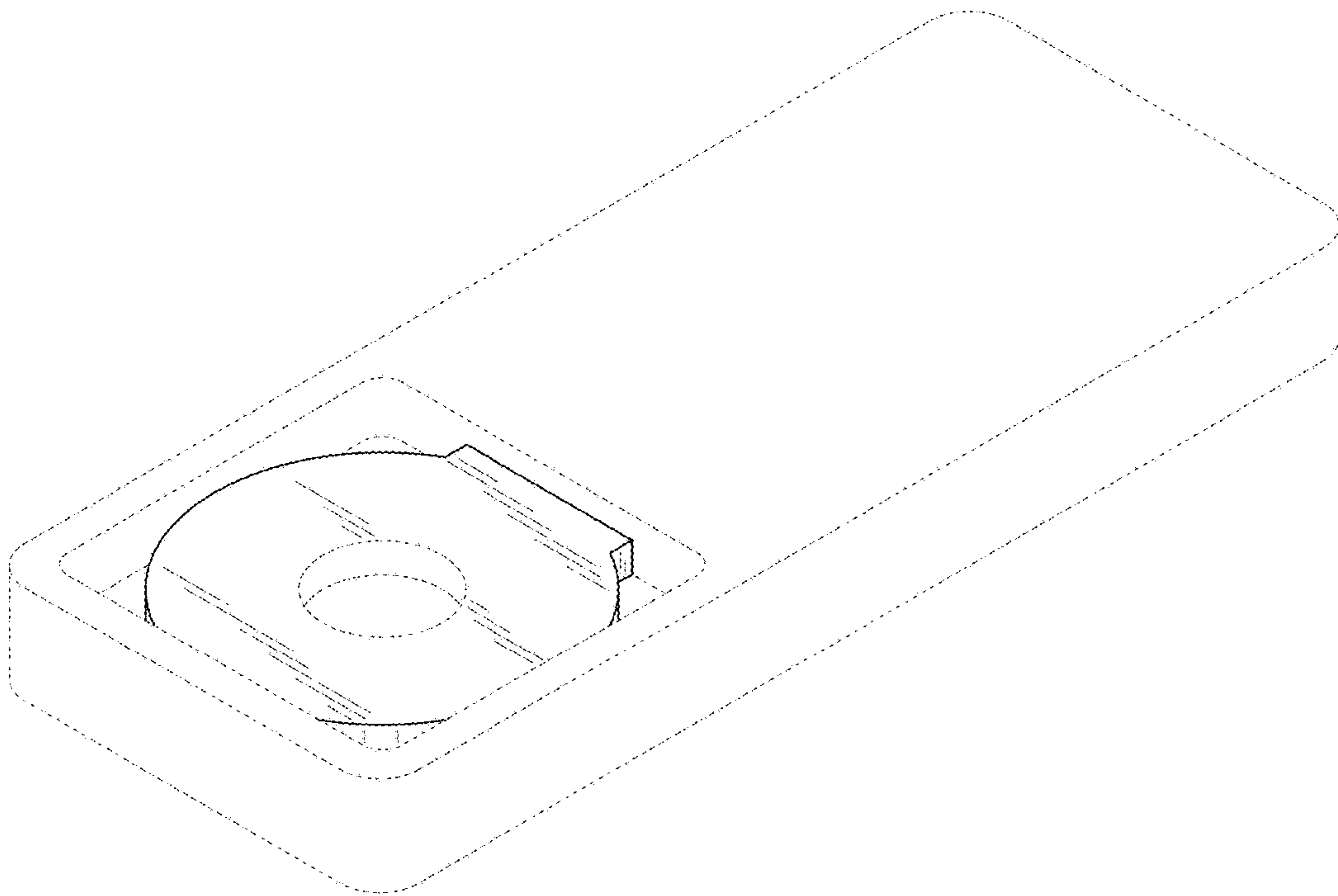
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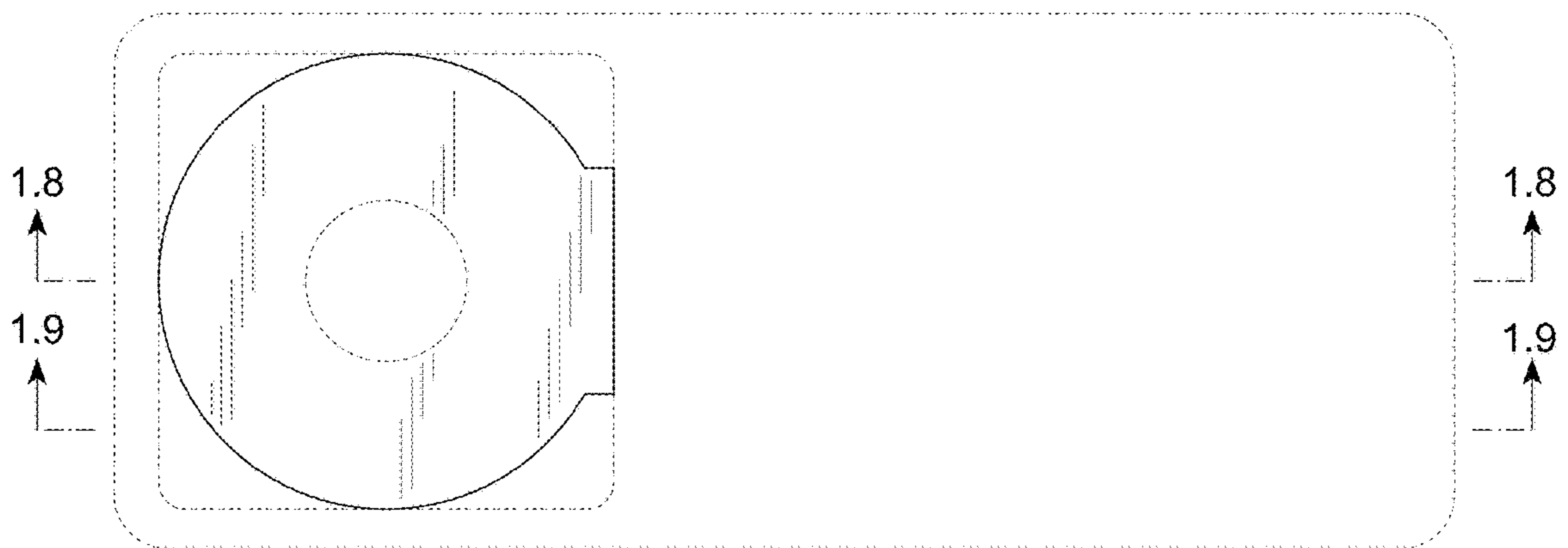
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1.1



1.2



**1.3**



1.4



**1.5**

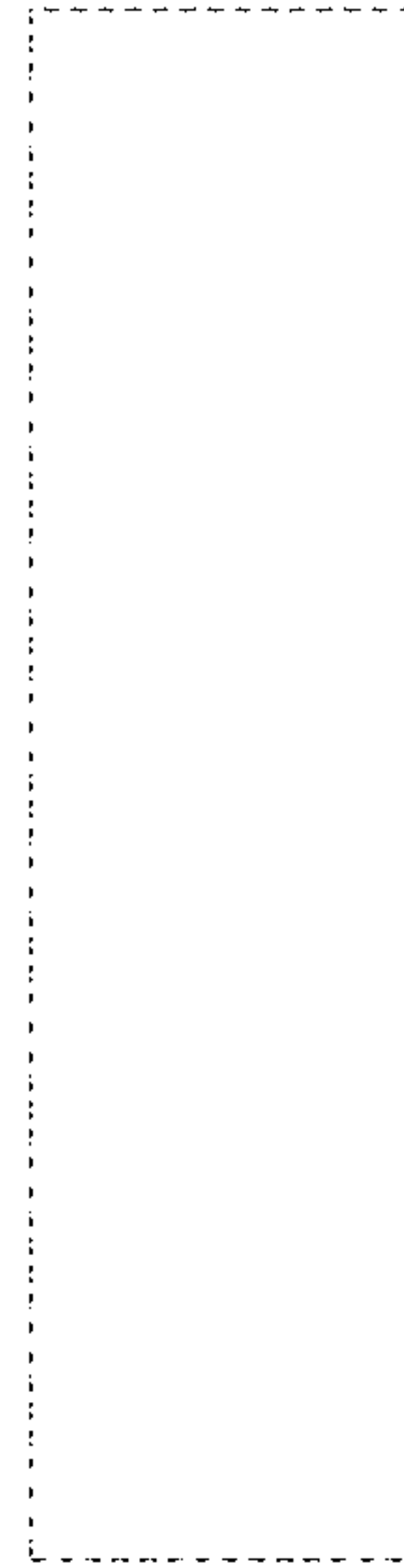


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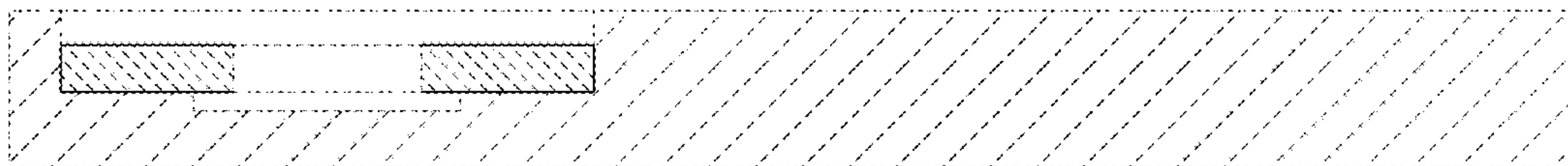




1.7



1.8



1.9

